

# μA75450/60/70 Series Dual Peripheral Drivers

Linear Division Interface Products

### Description

The μA75400 series of devices are dual high speed general purpose interface drivers that convert TTL and DTL logic levels to high current drive capability. The μA75450 features two TTL NAND gates and two uncommitted transistors. The μA75451, μA75452, and μA75453 feature two standard series 74 TTL gates in AND, NAND and OR configurations respectively, driving the base of two high voltage, high current, uncommitted collector output transistors.

The μA75400 series offers flexibility in designing high speed logic buffers, power drivers, lamp drivers, line drivers, MOS drivers, clock drivers, and memory drivers.

- No Latch-Up Up To 55 V
- High Output Current Capability
- TTL Or DTL Input Compatibility
- Input Clamp Diodes
- 5.0 V Supply Voltage

### Absolute Maximum Ratings

	μA75450	μA75451 μA75452 μA75453	μA75461 μA75462 μA75471 μA75472
Storage Temperature Range <sup>1</sup>			
Ceramic DIP	-65°C to +175°C	-65°C to +175°C	
Molded DIP and SO-8	-65°C to +150°C	-65°C to +150°C	
Operating Temperature Range	0°C to +70°C	0°C to +70°C	
Lead Temperature			
Ceramic DIP (soldering, 60 s)	300°C	300°C	
Molded DIP and SO-8 (soldering, 10 s)	265°C	265°C	
Internal Power Dissipation <sup>2, 3</sup>			
14L-Ceramic DIP	1.36 W		
14L-Molded DIP	1.04 W		
8L-Ceramic DIP		1.30 W	
8L-Molded DIP		0.93 W	
SO-8		0.81 W	
Supply Voltage <sup>4</sup>	7.0 V	7.0 V	
Input Voltage <sup>4</sup>	5.5 V	5.5 V	
Inter-emitter Voltage <sup>5</sup>	5.5 V	5.5 V	
V <sub>CC</sub> to Substrate Voltage <sup>9</sup>	35 V		
Collector to Substrate Voltage <sup>9</sup>	35 V		
Collector to Base Voltage	35 V		
Collector to Emitter Voltage <sup>6</sup>	30 V		
Emitter to Base Voltage	5.0 V		
Output Voltage <sup>4 and 7</sup>			Table 2
Continuous Collector Current <sup>8</sup>	300 mA		
Continuous Output Current <sup>8</sup>			300 mA

### Notes

1. μA75452 is Molded DIP and SO-8 only.
2. T<sub>J Max</sub> = 175°C for the Ceramic DIP, and 150°C for the Molded DIP.
3. Ratings apply to ambient temperature at 25°C. Above this temperature, derate the 14L-Ceramic DIP at 9.1 mW/°C, the 14L-Molded DIP at 8.3 mW/°C, the 8L-Ceramic DIP at 8.7 mW/°C, and the 8L-Molded DIP at 7.5 mW/°C.
4. Voltage values are with respect to network ground terminal unless otherwise specified.

5. This is the voltage between two emitters of a multiple emitter input transistor.
6. This value applies when the base-emitter resistance (R<sub>BE</sub>) is equal to or less than 500 Ω.
7. This is the maximum voltage which should be applied to any output when it is in the off state.
8. Both halves of these dual circuits may conduct rated current simultaneously.
9. For the μA75450 only, the substrate (Lead 8), must always be at the most negative device voltage for proper operation.

# μA75450/60/70 Series

**Test Table 1** Operating Temperature Range and Supply Voltage Range

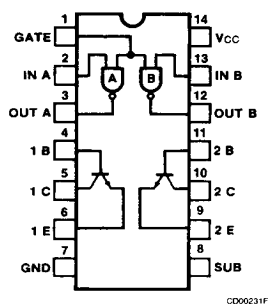
Symbol	Characteristic	μA75000 Series
$T_A$	Operating Temperature	0°C to 70°C
$V_{CC}$	Supply Voltage	+4.75 V to +5.25 V

**Test Table 2**

Symbol	Characteristic	μA7545X	μA75461 μA75462	μA75471 μA75472
$V_{OH}$	Maximum Output	30 V	35 V	80 V
$V_S$	Maximum, Latch-up	20 V	30 V	55 V

**μA75450**  
**Dual Positive AND Peripheral Drivers**

**Connection Diagram**  
**14-Lead DIP**  
**(Top View)**



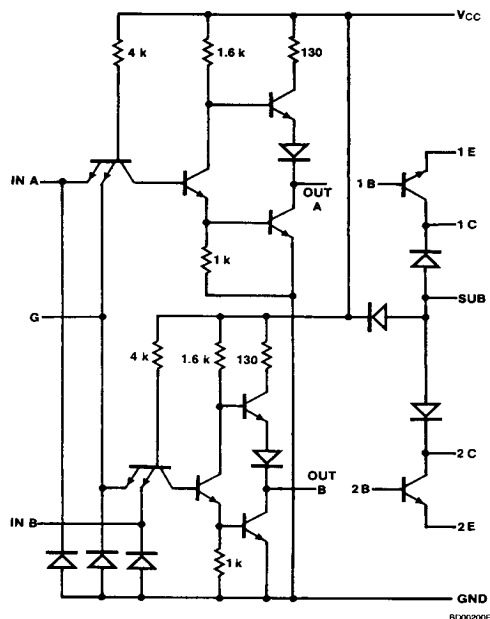
**Logic Function**

Positive Logic:  $Z = \overline{XY}$  (gate only)  
 $Z = XY$  (gate and transistor)

**Order Information**

Device Code	Package Code	Package Description
μA75450DC	6A	Ceramic DIP
μA75450PC	9A	Molded DIP

**Equivalent Circuit**



All resistor values in ohms

## μA75450/60/70 Series

### μA75450

**Electrical Characteristics** Over recommended operating temperature and supply voltage ranges, (use Test Table 1), unless otherwise indicated.

#### DC Characteristics

##### TTL Gates

Symbol	Characteristic		Condition	Test Figure	Min	Typ <sup>1</sup>	Max	Unit
V <sub>IH</sub>	Input Voltage HIGH			1	2.0			V
V <sub>IL</sub>	Input Voltage LOW			2			0.8	V
V <sub>IC</sub>	Input Clamp Diode Voltage		V <sub>CC</sub> = Min, I <sub>I</sub> = -12 mA	3			-1.5	V
V <sub>OH</sub>	Output Voltage HIGH		V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V, I <sub>OH</sub> = -400 μA	2	2.4	3.3		V
V <sub>OL</sub>	Output Voltage LOW		V <sub>CC</sub> = Min, V <sub>IH</sub> = 2.0 V, I <sub>OL</sub> = 16 mA	1		0.22	0.4	V
I <sub>I</sub>	Input Current at Maximum Input Voltage	Input A	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.5 V	4			1.0	mA
		Input G					2.0	
I <sub>IH</sub>	Input Current HIGH	Input A	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.4 V	4			40	μA
		Input G					80	
I <sub>IL</sub>	Input Current LOW	Input A	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.4 V	3			-1.6	mA
		Input G					-3.2	
I <sub>OS</sub>	Output Short Circuit Current <sup>2</sup>		V <sub>CC</sub> = Max	5	-18		-55	mA
I <sub>CCH</sub>	Supply Current HIGH		V <sub>CC</sub> = Max, V <sub>I</sub> = 0 V	6		2.0	4.0	mA
I <sub>CCL</sub>	Supply Current LOW		V <sub>CC</sub> = Max, V <sub>I</sub> = 5.0 V			6.0	11	

##### Output Transistors (Note 4)

Symbol	Characteristic	Condition	Min	Typ <sup>1</sup>	Max	Unit
V <sub>(BR)CBO</sub>	Collector to Base Breakdown Voltage	I <sub>C</sub> = 100 μA, I <sub>E</sub> = 0 μA	35			V
V <sub>(BR)CER</sub>	Collector to Base Breakdown Voltage	I <sub>C</sub> = 100 μA, R <sub>BE</sub> = 500 Ω	30			V
V <sub>(BR)EBO</sub>	Emitter to Base Breakdown Voltage	I <sub>E</sub> = 100 μA, I <sub>C</sub> = 0 μA	5.0			V
h <sub>FE</sub>	Static Forward Current Transfer Ratio <sup>3</sup>	V <sub>CE</sub> = 3.0 V, I <sub>C</sub> = 100 mA, T <sub>A</sub> = 25°C	25			
		V <sub>CE</sub> = 3.0 V, I <sub>C</sub> = 300 mA, T <sub>A</sub> = 25°C	30			
		V <sub>CE</sub> = 3.0 V, I <sub>C</sub> = 100 mA	20			
		V <sub>CE</sub> = 3.0 V, I <sub>C</sub> = 300 mA	25			
V <sub>BE(sat)</sub>	Base to Emitter Voltage <sup>3</sup>	I <sub>B</sub> = 10 mA, I <sub>C</sub> = 100 mA		0.85	1.0	V
		I <sub>B</sub> = 30 mA, I <sub>C</sub> = 300 mA		1.05	1.2	
V <sub>CE(sat)</sub>	Collector to Emitter Saturation Voltage <sup>3</sup>	I <sub>B</sub> = 10 mA, I <sub>C</sub> = 100 mA		0.25	0.4	V
		I <sub>B</sub> = 30 mA, I <sub>C</sub> = 300 mA		0.5	0.7	

## μA75450/60/70 Series

μA75450 (Cont.)

**Electrical Characteristics** Over recommended operating temperature and supply voltage ranges, (use Test Table 1), unless otherwise indicated.

**AC Characteristics**  $V_{CC} = 5.0 \text{ V}$ ,  $T_A = 25^\circ\text{C}$

### TTL Gates

Symbol	Characteristic	Condition	Test Figure	μA75450B			Unit
				Min	Typ	Max	
$t_{PLH}$	Propagation Delay Time, LOW to HIGH	$C_L = 15 \text{ pF}$ , $R_L = 400 \Omega$	12		12	22	ns
$t_{PHL}$	Propagation Delay Time, HIGH to LOW				8.0	15	ns

### Output Transistors

Symbol	Characteristic	Condition <sup>3</sup>	Test Figure	Min	Typ	Max	Unit
$t_d$	Delay Time	$I_C = 200 \text{ mA}$ , $V_{BE(off)} = -1.0 \text{ V}$ , $I_{B(1)} = 20 \text{ mA}$ , $I_{B(2)} = -40 \text{ mA}$ , $C_L = 15 \text{ pF}$ , $R_L = 50 \Omega$	13		8.0	15	ns
$t_r$	Rise Time				12	20	ns
$t_s$	Storage Time				7.0	15	ns
$t_f$	Fall Time				6.0	15	ns

### Gates and Transistors Combined

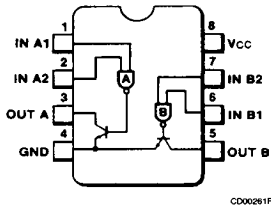
Symbol	Characteristic	Condition	Test Figure	Min	Typ	Max	Unit
$t_{PLH}$	Propagation Delay Time, LOW to HIGH	$I_C = 200 \text{ mA}$ , $C_L = 15 \text{ pF}$ , $R_L = 50 \Omega$	14		20	30	ns
$t_{PHL}$	Propagation Delay Time, HIGH to LOW				20	30	ns
$t_{TLH}$	Transition Time, LOW to HIGH				7.0	12	ns
$t_{THL}$	Transition Time, HIGH to LOW				9.0	15	ns
$V_{OH}$	HIGH Level Output Voltage After Switching	$V_I = 20 \text{ V}$ , $I_C \approx 300 \text{ mA}$ , $R_{BE} = 500 \Omega$	15	$V_I - 6.5$			mV

### Notes

- All typical values are at  $V_{CC} = 5.0 \text{ V}$ ,  $T_A = 25^\circ\text{C}$ .
- Not more than one output should be shorted at a time.
- These parameters must be measured using the pulse techniques.  
 $t_w = 300 \mu\text{s}$ , duty cycle  $\leq 2\%$ .
- Voltage and current values shown are nominal; exact values vary slightly with transistor parameter.

**μA75451, μA75461, μA75471**  
**Dual Positive AND Peripheral Drivers**

**Connection Diagram**  
**8-Lead DIP and SO-8 Package**  
**(Top View)**



**Truth Table**

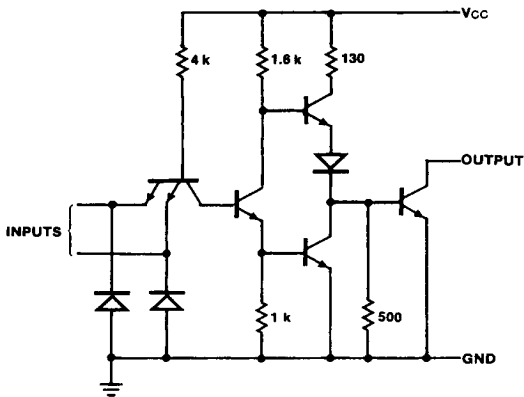
Inputs		Output
X	Y	Z
L	L	L (on state)
L	H	L (on state)
H	L	L (on state)
H	H	H (off state)

H = HIGH Level, L = LOW Level

**Order Information**

Device Code	Package Code	Package Description
μA75451RC	6T	Ceramic DIP
μA75451SC	KC	Molded Surface Mount
μA75451TC	9T	Molded DIP
μA75461TC	9T	Molded DIP
μA75471TC	9T	Molded DIP

**Equivalent Circuit (1/2 of Circuit)**



**Notes**

Component values shown are nominal.  
 All resistor values in ohms.

## μA75450/60/70 Series

### μA75451

**Electrical Characteristics** Over recommended operating temperature and supply voltage ranges, (use Test Table 1), unless otherwise indicated.

#### DC Characteristics

Symbol	Characteristic	Condition	Test Figure	μA75451			Unit
				Min	Typ <sup>1</sup>	Max	
V <sub>IH</sub>	Input Voltage HIGH		7	2.0			V
V <sub>IL</sub>	Input Voltage LOW		7			0.8	V
V <sub>CD</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = -12 mA	8			-1.5	V
I <sub>OH</sub>	Output Current HIGH <sup>2</sup>	V <sub>CC</sub> = Min, V <sub>IH</sub> = 2.0 V	7			100	μA
V <sub>OL</sub>	Output Voltage LOW	V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 100 mA	7		0.25	0.4	V
		V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 300 mA			0.5	0.7	
I <sub>I</sub>	Input Current at Maximum Input Voltage	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.5 V	9			1.0	mA
I <sub>IH</sub>	Input Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.4 V	9			40	μA
I <sub>IL</sub>	Input Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.4 V	8		-1.0	-1.6	mA
I <sub>CCH</sub>	Supply Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.0 V	10		7.0	11	mA
I <sub>CCL</sub>	Supply Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 0 V			52	65	mA

#### AC Characteristics V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C

Symbol	Characteristic	Condition	Test Figure	Min	Typ	Max	Unit
t <sub>PLH</sub>	Propagation Delay Time, LOW to HIGH	I <sub>O</sub> ≈ 200 mA, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 50 Ω	14		18	25	ns
t <sub>PHL</sub>	Propagation Delay Time, HIGH to LOW				25	25	ns
t <sub>TLH</sub>	Transition Time, LOW to HIGH				5.0	8.0	ns
t <sub>THL</sub>	Transition Time, HIGH to LOW				7.0	12	ns
V <sub>OH</sub>	HIGH Level Output Voltage After Switching <sup>3</sup>	I <sub>O</sub> ≈ 300 mA	15	V <sub>I</sub> -6.5			mV

## μA75450/60/70 Series

### μA75461, μA75471

**Electrical Characteristics** Over recommended operating temperature and supply voltage ranges, (use Test Table 1), unless otherwise indicated.

#### DC Characteristics

Symbol	Characteristic	Condition	Test Figure	μA75461			μA75471			Unit
				Min	Typ <sup>1</sup>	Max	Min	Typ <sup>1</sup>	Max	
V <sub>IH</sub>	Input Voltage HIGH		7	2.0			2.0			V
V <sub>IL</sub>	Input Voltage LOW		7			0.8			0.8	V
V <sub>IC</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = -12 mA	8		-1.2	-1.5		-1.2	-1.5	V
I <sub>OH</sub>	Output Current HIGH <sup>2</sup>	V <sub>CC</sub> = Min, V <sub>IH</sub> = 2.0 V	7			100			100	μA
V <sub>OL</sub>	Output Voltage LOW	V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 100 mA	7		0.16	0.4		0.16	0.4	V
		V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 300 mA			0.35	0.7		0.35	0.7	
I <sub>I</sub>	Input Current at Maximum Input Voltage	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.5 V	9			1.0			1.0	mA
I <sub>IH</sub>	Input Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.4 V	9			40			40	μA
I <sub>IL</sub>	Input Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.4 V	8		-1.0	-1.6		-1.0	-1.6	mA
I <sub>CCH</sub>	Supply Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.0 V	10		8.0	11		8.0	11	mA
I <sub>CCL</sub>	Supply Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 0 V			61	76		61	76	mA

#### AC Characteristics V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C

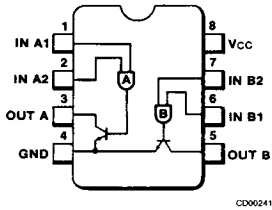
Symbol	Characteristic	Condition	Test Figure	μA75461			μA75471			Unit
				Min	Typ	Max	Min	Typ	Max	
t <sub>PLH</sub>	Propagation Delay Time, LOW to HIGH	I <sub>O</sub> ≈ 200 mA, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 50 Ω	14		35	55		35	55	ns
t <sub>PHL</sub>	Propagation Delay Time, HIGH to LOW				25	40		25	40	ns
t <sub>TLH</sub>	Transition Time, LOW to HIGH				8	20		8.0	20	ns
t <sub>THL</sub>	Transition Time, HIGH to LOW				10	20		10	20	ns
V <sub>OH</sub>	HIGH Level Output Voltage After Switching <sup>3</sup>	I <sub>O</sub> ≈ 300 mA	15	V <sub>I</sub> - 10			V <sub>I</sub> - 18			mV

#### Notes

- All typical values are at V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C.
- V<sub>OH</sub> = 30 V for μA75451, 35 V for μA75461, 80 V for μA75471.
- V<sub>I</sub> = 20 V for μA75451, 30 V for μA75461, 55 V for μA75471.

**μA75452, μA75462, μA75472**  
**Dual Positive NAND Peripheral Driver**

**Connection Diagram**  
**8-Lead DIP and SO-8 Package**  
**(Top View)**



CD00241F

**Truth Table**

Inputs		Output
1	2	
L	L	H (off state)
L	H	H (off state)
H	L	H (off state)
H	H	L (on state)

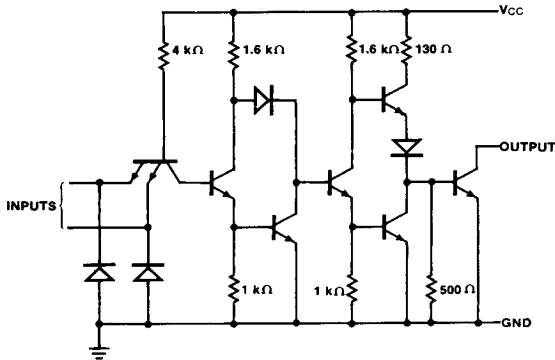
H = HIGH Level, L = LOW Level

**Order Information**

Device Code	Package Code	Package Description
μA75452SC	KC	Molded Surface Mount
μA75452TC	9T	Molded DIP
μA75462TC	9T	Molded DIP
μA75472TC	9T	Molded DIP

9

**Equivalent Circuit (1/2 of Circuit)**



BD00221F

**Notes**

Component values shown are nominal.  
 All resistor values in ohms.



## μA75450/60/70 Series

### μA75452

**Electrical Characteristics** Over recommended operating temperature and supply voltage ranges, (use Test Table 1), unless otherwise indicated.

#### DC Characteristics

Symbol	Characteristic	Condition	Test Figure	μA75452B			Unit
				Min	Typ <sup>1</sup>	Max	
V <sub>IH</sub>	Input Voltage HIGH		7	2.0			V
V <sub>IL</sub>	Input Voltage LOW		7			0.8	V
V <sub>IC</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = -12 mA	8			-1.5	V
I <sub>OH</sub>	Output Current HIGH <sup>2</sup>	V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V	7			100	μA
V <sub>OL</sub>	Output Voltage LOW	V <sub>CC</sub> = Min, V <sub>IH</sub> = 2.0 V, I <sub>OL</sub> = 100 mA	7		0.25	0.4	V
		V <sub>CC</sub> = Min, V <sub>IH</sub> = 2.0 V, I <sub>OL</sub> = 300 mA			0.5	0.7	
I <sub>I</sub>	Input Current at Maximum Input Voltage	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.5 V	9			1.0	mA
I <sub>IH</sub>	Input Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.4 V	9			40	μA
I <sub>IL</sub>	Input Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.4 V	8		-1.0	-1.6	mA
I <sub>CCH</sub>	Supply Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 0 V	10		11	14	mA
I <sub>CCL</sub>	Supply Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.0 V			56	71	

### μA75452

**AC Characteristics** V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C

Symbol	Characteristic	Condition	Test Figure	Min	Typ	Max	Unit
t <sub>PLH</sub>	Propagation Delay Time, LOW to HIGH	I <sub>O</sub> ≈ 200 mA, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 50 Ω	14		25	35	ns
t <sub>PHL</sub>	Propagation Delay Time, HIGH to LOW				22	35	
t <sub>TLH</sub>	Transition Time, LOW to HIGH				5.0	8.0	
t <sub>THL</sub>	Transition Time, HIGH to LOW				7.0	12	
V <sub>OH</sub>	HIGH Level Output Voltage After Switching <sup>3</sup>	I <sub>O</sub> ≈ 300 mA	15	V <sub>I</sub> - 6.5			mV

# μA75450/60/70 Series

## μA75462/μA75472

**Electrical Characteristics** Over recommended operating temperature and supply voltage ranges, (use Test Table 1), unless otherwise indicated.

### DC Characteristics

Symbol	Characteristic	Condition	Test Figure	μA75462			μA75472			Unit
				Min	Typ <sup>1</sup>	Max	Min	Typ <sup>1</sup>	Max	
V <sub>IH</sub>	Input Voltage HIGH		7	2.0			2.0			V
V <sub>IL</sub>	Input Voltage LOW		7			0.8			0.8	V
V <sub>CD</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = -12 mA	8		-1.2	-1.5	-1.2	-1.5		V
I <sub>OH</sub>	Output Current HIGH <sup>2</sup>	V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V	7			100			100	μA
V <sub>OL</sub>	Output Voltage LOW	V <sub>CC</sub> = Min, V <sub>IH</sub> = 2.0 V, I <sub>OL</sub> = 100 mA	7		0.16	0.4	0.16	0.4		V
		V <sub>CC</sub> = Min, V <sub>IH</sub> = 2.0 V, I <sub>OL</sub> = 300 mA			0.35	0.7	0.35	0.7		
I <sub>I</sub>	Input Current at Maximum Input Voltage	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.5 V	9			1.0			1.0	mA
I <sub>IH</sub>	Input Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.4 V	9			40			40	μA
I <sub>IL</sub>	Input Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.4 V	8		-1.0	-1.6	-1.0	-1.6		mA
I <sub>CCH</sub>	Supply Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 0 V	10		13	17	13	17		mA
I <sub>CCL</sub>	Supply Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.0 V			65	76	65	76		mA

### AC Characteristics V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C

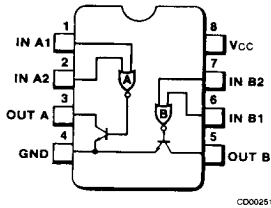
Symbol	Characteristic	Condition	Test Figure	μA75462			μA75472			Unit
				Min	Typ	Max	Min	Typ	Max	
t <sub>PLH</sub>	Propagation Delay Time, LOW to HIGH	I <sub>O</sub> ≈ 200 mA, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 50 Ω	14		50	65		45	65	ns
t <sub>PHL</sub>	Propagation Delay Time, HIGH to LOW				40	50		30	50	ns
t <sub>TLH</sub>	Transition Time, LOW to HIGH				12	25		13	25	ns
t <sub>THL</sub>	Transition Time, HIGH to LOW				15	20		10	20	ns
V <sub>OH</sub>	HIGH Level Output Voltage After Switching <sup>3</sup>	I <sub>O</sub> ≈ 300 mA	15	V <sub>I</sub> - 10			V <sub>I</sub> - 18			mV

#### Notes

- All typical values are at V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C.
- V<sub>OH</sub> = 30 V for μA75452, 35 V for μA75462, 80 V for μA75472.
- V<sub>S</sub> = 20 V for μA75452, 30 V for μA75462 and 55 V for μA75472.

**μA75453**  
**Dual Positive OR Peripheral Drivers**

**Connection Diagram**  
**8-Lead DIP and SO-8 Package**  
**(Top View)**



CD00251F

**Truth Table**

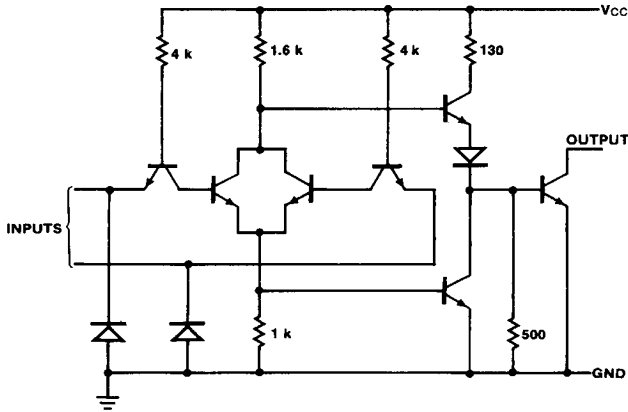
Inputs		Output
1	2	
L	L	L (on state)
L	H	H (off state)
H	L	H (off state)
H	H	H (off state)

H = HIGH Level, L = LOW Level

**Order Information**

Device Code	Package Code	Package Description
μA75453RC	6T	Ceramic DIP
μA75453SC	KC	Molded Surface Mount
μA75453TC	9T	Molded DIP

**Equivalent Circuit (1/2 of Circuit)**



BD00281F

**Notes**

Component values shown are nominal.  
 All resistor values in ohms.

# μA75450/60/70 Series

## μA75453

**Electrical Characteristics** Over recommended operating temperature and supply voltage ranges, (use Test Table 1), unless otherwise indicated.

### DC Characteristics

Symbol	Characteristic	Condition	Test Figure	Min	Typ <sup>1</sup>	Max	Unit
V <sub>IH</sub>	Input Voltage HIGH		7	2.0			V
V <sub>IL</sub>	Input Voltage LOW		7			0.8	V
V <sub>IC</sub>	Input Clamp Diode Voltage	V <sub>CC</sub> = Min, I <sub>I</sub> = -12 mA	8			-1.5	V
I <sub>OH</sub>	Output Current HIGH	V <sub>CC</sub> = Min, V <sub>OH</sub> = 30 V, V <sub>IH</sub> = 2.0 V	7			100	μA
V <sub>OL</sub>	Output Voltage LOW	V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 100 mA	7		0.25	0.4	V
		V <sub>CC</sub> = Min, V <sub>IL</sub> = 0.8 V, I <sub>OL</sub> = 300 mA			0.5	0.7	
I <sub>I</sub>	Input Current at Maximum Input Voltage	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.5 V	9			1.0	mA
I <sub>IH</sub>	Input Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 2.4 V	9			40	μA
I <sub>IL</sub>	Input Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 0.4 V	8		-1.0	-1.6	mA
I <sub>CCH</sub>	Supply Current HIGH	V <sub>CC</sub> = Max, V <sub>I</sub> = 5.0 V	11		8.0	11	mA
I <sub>CCL</sub>	Supply Current LOW	V <sub>CC</sub> = Max, V <sub>I</sub> = 0 V			54	68	mA

9

### AC Characteristics V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C

Symbol	Characteristic	Condition	Test Figure	μA75453			Unit
				Min	Typ	Max	
t <sub>PLH</sub>	Propagation Delay Time, LOW to HIGH	I <sub>O</sub> ≈ 200 mA, C <sub>L</sub> = 15 pF, R <sub>L</sub> = 50 Ω	14		18	25	ns
t <sub>PHL</sub>	Propagation Delay Time, HIGH to LOW				16	25	ns
t <sub>TLH</sub>	Transition Time, LOW to HIGH				5.0	8.0	ns
t <sub>THL</sub>	Transition Time, HIGH to LOW				7.0	12	ns
V <sub>OH</sub>	HIGH Level Output Voltage After Switching	V <sub>I</sub> = 20 V, I <sub>O</sub> ≈ 300 mA	15	V <sub>I</sub> - 6.5			mV

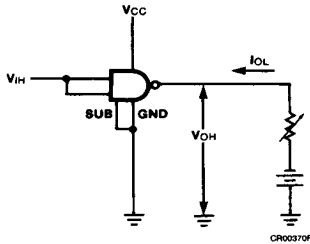
#### Notes

1. All typical values are at V<sub>CC</sub> = 5.0 V, T<sub>A</sub> = 25°C.

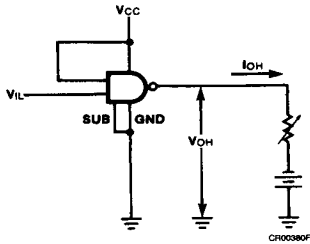
**Characteristics Measurement Information**

**DC Test Circuits (Note 1)**

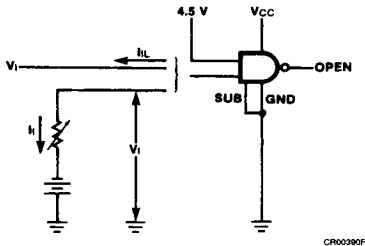
**Figure 1**  $V_{IH}$ ,  $V_{OL}$  (Note 2)



**Figure 2**  $V_{IL}$ ,  $V_{OH}$  (Note 3)



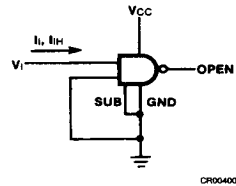
**Figure 3**  $V_{IC}$ ,  $I_{IL}$  (Notes 3 and 4)



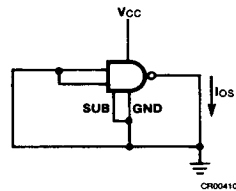
**Notes**

1. Arrows indicate actual direction of current flow. Current into a terminal is a positive value.
2. Both inputs are tested simultaneously.
3. Each input is tested separately.
4. When testing  $V_{IC}$ , input not under test is open.
5. Each gate is tested separately.
6. Both gates are tested simultaneously.

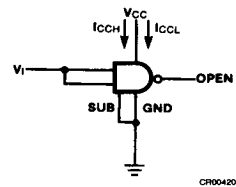
**Figure 4**  $I_I$ ,  $I_{IH}$  (Note 3)



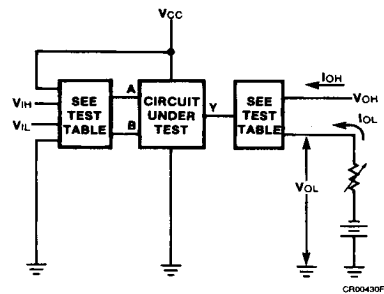
**Figure 5**  $I_{OS}$  (Note 5)



**Figure 6**  $I_{CCH}$ ,  $I_{CCL}$  (Note 6)



**Figure 7**  $V_{IH}$ ,  $V_{IL}$ ,  $I_{OH}$ ,  $V_{OL}$  (Note 3)



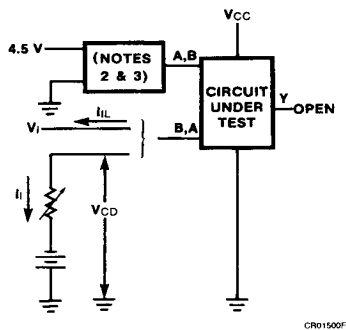
Characteristics Measurement Information (Cont.)

DC Test Circuits (Note 5)

Test Table 2

Circuit	Input Under Test	Other Input	Output	
			Apply	Measure
μA754X1	V <sub>IH</sub> V <sub>IL</sub>	V <sub>IH</sub> V <sub>CC</sub>	V <sub>OH</sub> I <sub>OL</sub>	I <sub>OH</sub> V <sub>OL</sub>
μA754X2	V <sub>IH</sub> V <sub>IL</sub>	V <sub>IH</sub> V <sub>CC</sub>	I <sub>OL</sub> V <sub>OH</sub>	V <sub>OL</sub> I <sub>OH</sub>
μA754X3	V <sub>IH</sub> V <sub>IL</sub>	GND V <sub>IL</sub>	V <sub>OH</sub> I <sub>OL</sub>	I <sub>OH</sub> V <sub>OL</sub>

Figure 8 V<sub>IC</sub>, I<sub>IL</sub> (Note 1)



Notes

1. Each input is tested separately.
2. When testing I<sub>IL</sub> μA75400, the input not under test is grounded. For all other circuits it is at 4.5 V.
3. When testing V<sub>IC</sub>, input not under test is open.
4. Both gates are tested simultaneously.
5. Arrows indicate actual direction of current flow. Current into a terminal is a position value.

Figure 9 I<sub>I</sub>, I<sub>IH</sub> (Note 1)

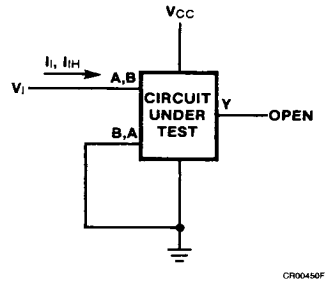


Figure 10 I<sub>CCH</sub>, I<sub>CCL</sub> for AND, NAND Circuits (Note 4)

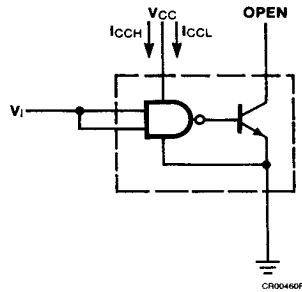
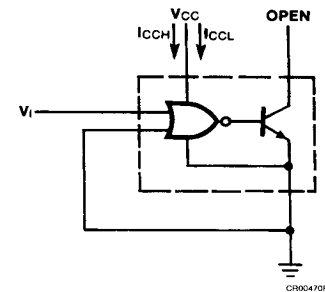


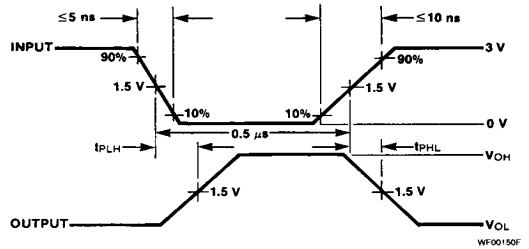
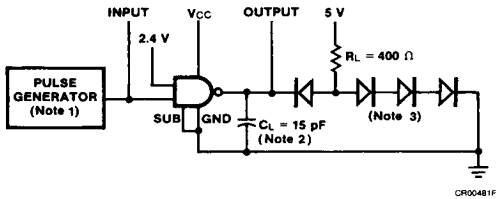
Figure 11 I<sub>CCH</sub>, I<sub>CCL</sub> for OR, NOR Circuits (Note 4)



Characteristics Measurement Information (Cont.)

Switching Characteristics

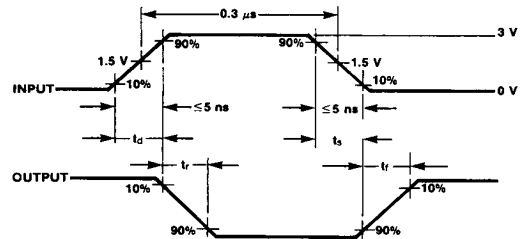
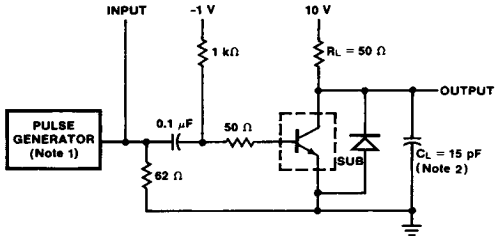
Figure 12 Propagation Delay Times, Each Gate (μA75450 Only)



Notes

1. The pulse generator has the following characteristics:  
PRR = 1.0 MHz,  $Z_O \approx 50 \Omega$ .
2.  $C_L$  includes probe and jig capacitance.
3. All diodes are FD777.

Figure 13 Switching Times, Each Transistor (μA75450 Only)



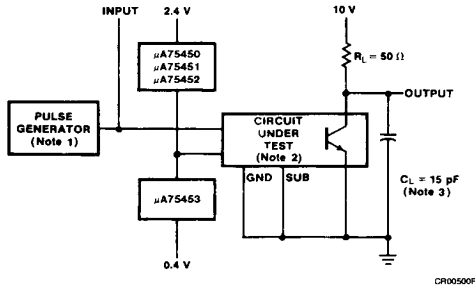
Notes

1. The pulse generator has the following characteristics:  
duty cycle  $\leq 1\%$ ,  $Z_O \approx 50 \Omega$ .
2.  $C_L$  includes probe and jig capacitance.

Characteristics Measurement Information (Cont.)

Switching Characteristics

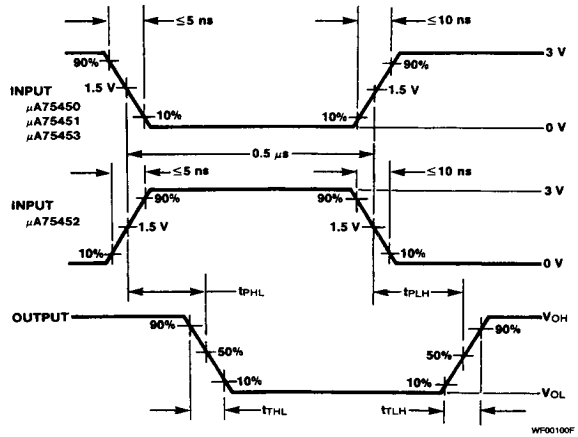
Figure 14 Switching Times of Complete Drivers



CR00500F

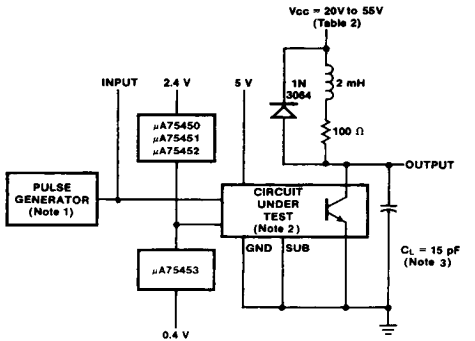
Notes

1. The pulse generator has the following characteristics:  
PRR = 1.0 MHz,  $Z_0 \approx 50 \Omega$ .
2. When testing μA75450, connect output Y to transistor base with a 500 Ω resistor to ground.
3.  $C_L$  includes probe and jig capacitance.



WF00100F

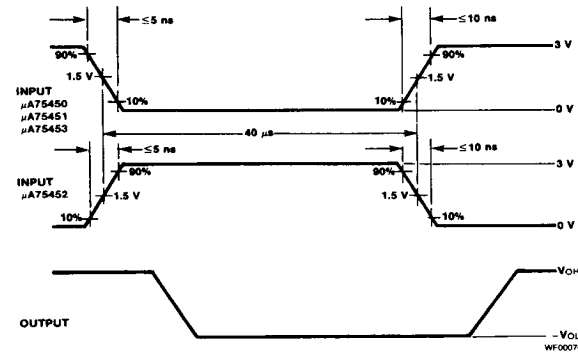
Figure 15 Latch-up Test of Complete Drivers



CR00511F

Notes

1. The pulse generator has the following characteristics:  
PRR = 12.5 kHz,  $Z_0 \approx 50 \Omega$ .
2. When testing μA75450, connect output Y to transistor base with a 500 Ω resistor from there to ground, and ground the substrate terminal.
3.  $C_L$  includes probe and jig capacitance.



WF00070F